

## Edge-TCT measurements of heavily irradiated HPK p-type sensors

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HPK p-type sensor was irradiated in steps with reactor neutrons up to the fluence of  $1e16$  cm<sup>-2</sup>. After each step several Edge-TCT measurements were performed during initial stage of annealing. Charge collection properties, drift velocity profiles were investigated as a function of annealing, fluence and bias voltage.

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